| | Application No. | Applicant(s) | |
|--|---|--------------------------------------|--------------------|
| Notice of Allowability | 10/039,126 | KIM ET AL. | |
| | Examiner | Art Unit | T |
| | David Nhu | 2818 | Bu |
| The MAILING DATE of this communication appears on the cover sheet with the correspondence address All claims being allowable, PROSECUTION ON THE MERITS IS (OR REMAINS) CLOSED in this application. If not included herewith (or previously mailed), a Notice of Allowance (PTOL-85) or other appropriate communication will be mailed in due course. THIS NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIGHTS. This application is subject to withdrawal from issue at the initiative of the Office or upon petition by the applicant. See 37 CFR 1.313 and MPEP 1308. | | | |
| 1. This communication is responsive to 4/6/04. | | | |
| 2. X The allowed claim(s) is/are <u>1-5,7-12 and 14-17.</u> | | | |
| 3. $igotimes$ The drawings filed on <u>03 January 2002</u> are accepted by the | e Examiner. | | |
| 4. Acknowledgment is made of a claim for foreign priority unall a) All b) Some* c) None of the: 1. Certified copies of the priority documents have 2. Certified copies of the priority documents have 3. Copies of the certified copies of the priority documents have International Bureau (PCT Rule 17.2(a)). * Certified copies not received: | been received. been received in Application No | | tion from the |
| Applicant has THREE MONTHS FROM THE "MAILING DATE" of this communication to file a reply complying with the requirements noted below. Failure to timely comply will result in ABANDONMENT of this application. THIS THREE-MONTH PERIOD IS NOT EXTENDABLE. | | | |
| A SUBSTITUTE OATH OR DECLARATION must be subm INFORMAL PATENT APPLICATION (PTO-152) which give | itted. Note the attached EXAMINER es reason(s) why the oath or declara | 'S AMENDMENT or Nation is deficient. | OTICE OF |
| 6. CORRECTED DRAWINGS (as "replacement sheets") mus | st be submitted. | | |
| (a) ☐ including changes required by the Notice of Draftsperson's Patent Drawing Review (PTO-948) attached | | | |
| 1) hereto or 2) to Paper No./Mail Date | | | |
| (b) ☐ including changes required by the attached Examiner's Amendment / Comment or in the Office action of Paper No./Mail Date | | | |
| Identifying indicia such as the application number (see 37 CFR 1 each sheet. Replacement sheet(s) should be labeled as such in the | .84(c)) should be written on the drawin he header according to 37 CFR 1.121(| ngs in the front (not the d). | back) of |
| 7. DEPOSIT OF and/or INFORMATION about the deposit of BIOLOGICAL MATERIAL must be submitted. Note the attached Examiner's comment regarding REQUIREMENT FOR THE DEPOSIT OF BIOLOGICAL MATERIAL. | | | |
| Attachment(s) | E Notice of Informal E | Octont Application (PT) | D 152) |
| Notice of References Cited (PTO-892) Notice of Draftperson's Patent Drawing Review (PTO-948) | 5. ☐ Notice of Informal F6. ☐ Interview Summary | | J-102 _j |
| | Paper No./Mail Da | te | |
| Information Disclosure Statements (PTO-1449 or PTO/SB/C Paper No./Mail Date 01 | | | |
| 4. Examiner's Comment Regarding Requirement for Deposit | 8. 🖾 Examiner's Stateme | ent of Reasons for Allo | owance |
| of Biological Material | 9. | D | |
| | & auis | Zfr | |
| | <i>V</i> S | | |

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REASONS FOR ALLOWANCE

1. Claims 1-5, 7-12, 14-17 are allowed.

2. The following is an examiner's statement of reasons for allowance: None of the references of record teaches or suggests as cited in claims 1, 10: a conductive region formed in a top portion of the substrate adjacent a sidewall of the charge storage region; a source electrode on the conductive region, wherein the source electrode is electrically isolated from the control gate by a source-side insulative spacer; and a gate mask on the control gate, wherein the gate mask is in the shapes of a spacer, the gate mask having a width that is substantially equal to a width of the underlying charge storage region and a width of the control gate, wherein the source electrode is of a height that is equal to or lower than a top of the gate mask (as cited in claim 1); a gate mask on an entire top surface of the control gate and being in the shape of a spacer, the gate mask having a width that is substantially equal to a width of the underlying charge storage region and a width of the control gate (as cited in claim 10).

3. Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Conclusion

4. The prior art made of record and not relied upon is considered pertinent to applicant's disclosure: Chang (6,125,060): Flash EEPROM Device Employing Polysilicon Sidewall Spacer as an Erase Gate.

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5. Any inquiry concerning this communication on earlier communications from the examiner should be directed to David Nhu, (571)272-1792. The examiner can normally be reached on Monday-Friday from 7:30 AM to 5:00 PM.

The examiner's supervisor, David Nelms can be reached on (571)272-1787.

The fax phone number for the organization where this application or proceeding is assigned is (703)872-9306.

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is (703) 308-0956

David Nhu

DW

April 7, 2004

DAVID NHU PRIMARY EXAMINER